

Nov. 6, 2003

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Form PTO-1449 (Modified)		Atty Docket No.: 42P17821		S rial No.: Unknown		
List of Patents and Publications Statement (Use several sheets if necessary)				Applicant: Justin K. Brask et al.		
				Filing Dat : Herewith		

REFERENCE DESIGNATION			U.S. PATENT DOCUMENTS			
Examiner Initials		Document No.		Class	Sub-Class	Filing date if appropriate
K-cc	AA	5,625,217	Chau et al.	257	412	
	AB	5,753,560	Hong et al.	438	402	
	AC	5,783,478	Chau et al.	438	592	
	AD	5,891,798	Doyle et al.	438	624	
	AE	6,063,698	Tseng et al.	438	585	
	AF	6,087,261	Nishikawa et al.	438	685	
	AG	6,121,094	Gardner et al.	438	287	
	AH	6,184,072	Kaushik et al.	438	197	
	AI	6,306,742 B1	Doyle et al.	438	591	
	AJ	6,391,802 B1	Delpach et al.	438	785	
	AK	6,420,279	Ono et al.	438	785	
	AL	6,436,777	Ota	438	305	
	AM	6,475,874	Xiang et al.	438	396	
	AN	6,514,828	Ahn et al.	438	240	
	AO	6,544,906	Rotondaro et al.	438	785	
	AP	6,617,209	Chau et al.	438	240	
	AQ	6,617,210	Chau et al.	438	240	
	AR	US2002/0197790	Kizilyalli et al.	438	240	
K-cc	AS	US2003/0032303	Yu et al.	438	770	

FOREIGN PATENT DOCUMENTS							
		Document No.	Date	Country	Class	Sub-Class	Translation
	AT						
	AU						

OTHER ART (Including Author, Title, Date, Pertinent Pages, etc.)		
K-cc	AV	Polishchuk et al. "Dual Workfunction CMOS Gate Technology Based on Metal Interdiffusion," www.eesc.berkeley.edu , 1 page
	AW	Doug Barlage et al., "High-Frequency Response of 100nm Integrated CMOS Transistors with High-K Gate Dielectrics", 2001 IEEE, 4 pages.
	AX	Robert Chau et al., "A 50nm Depleted-Substrate CMOS Transistor (DST), 2001 IEEE, 4 pages.
	AY	Lu et al., "Dual-Metal Gate Technology for Deep-Submicron CMOS Devices", dated April 29, 2003, 1 page.
	AZ	Schwantes et al., "Performance Improvement of Metal Gate CMOS Technologies with Gigabit Feature Sizes", Technical University of Hamburg-Harburg, 5 pages.
	BA	Parker et al., "A Method of Making Semiconductor Device Having a High-K Gate Dielectric", Serial No. 10/285,915, Filed October 31, 2002
	BB	Chau et al., "A Method of Making Semiconductor Device Having a High-K Gate Dielectric", Serial No. 10/288,043, Filed November 5, 2002
	BC	Parker et al., "A Method of Making Semiconductor Device Having a High-K Gate Dielectric", Serial No. 10/315,268, Filed December 10, 2002
	BD	Doczy et al., "A Method of Making Semiconductor Device Having a High-K Gate Dielectric", Serial No. 10/338,174, Filed January 7, 2003
K-cc	BE	Brask et al., "A Method of Making Semiconductor Device Having a High-K Gate Dielectric", Serial No. 10/387,303, Filed March 11, 2003

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K-cc	BF	Brask et al., "A Method of Making Semiconductor Device Having a High-K Gate Dielectric", Serial No. 10/391,816, Filed March 18, 2003
	BG	Chau et al., "A Method for Making a Semiconductor Device Having a Metal Gate Electrode", Serial No. 10/431,166, Filed May 6, 2003
	BH	Brask, et al, "A Method for Making a Semiconductor Device Having a High-K Gate Dielectric", Serial No. 10/441,616, filed May 20, 2003
	BI	Brask et al. "A Selective Etch Process for Making a Semiconductor Device Having a High-K Gate Dielectric," Serial No. 10/652,546, filed August 28, 2003
	BJ	Brask et al. "A Method for Making a Semiconductor Device Having a High-K Gate Dielectric," Serial No. 10/642,796, filed August 28, 2003
K-cc	BK	Brask, "Methods and Compositions for Selectively Etching Metal Films and Structures," Serial No. 10/658,225, filed September 8, 2003
Examiner K.C. [Signature]		Date Considered 7-25-05
EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.		

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Form PTO-1449 (Modified)		Atty Docket No.: P17821		Serial No.: 10/704,498	
<div style="position: relative; height: 100px;"> <div style="position: absolute; top: 0; left: 0; width: 100%; height: 100%; background: repeating-linear-gradient(45deg, transparent, transparent 2px, black 2px, black 4px); opacity: 0.5;"></div> <div style="position: absolute; top: 0; left: 0; width: 100%; height: 100%; border: 1px solid black; border-radius: 50%; text-align: center; font-weight: bold;"> OIPF DEC 23 2003 PATENT & TRADEMARK OFFICE </div> </div>				Applicant: Justin K. Brask et al.	
				Filing Date: November 6, 2003	
REFERENCE DESIGNATION				U.S. PATENT DOCUMENTS	
Examiner Initials		Document No.		Class.	Sub-Class
K-cc	AA	US2003/0045080 A1	Visokay et al.	438	591
	AB				
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List of Patents and Publications Statement (Use several sheets if necessary) <div style="border: 1px solid black; border-radius: 50%; padding: 5px; display: inline-block; margin-top: 10px;"> NOV 26 2003 Vol. 26 </div>				Applicant: Justin K. Brask et al.	
				Filing Date: November 6, 2003	

REFERENCE DESIGNATION			U.S. PATENT DOCUMENTS			
Examiner Initials	Document No.	Document No.	Class	Sub-Class	Filing date if appropriate	
K-CC	AA	6,642,131 B2	Harada	438	591	
K-CC	AB	6,667,246 B2	Mitsuhashi et al.	438	756	
K-CC	AC	6,794,234 B2	Polishchuk et al.	438	199	
	AD					
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Examiner <i>K. C. [Signature]</i>	Date Considered <i>7-25-05</i>
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